Search Notes



| Application/Control No. | |
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10748657

Applicant(s)/Patent Under Reexamination

LEE, KYOUNG-JAE

Examiner

Koziol, Stephen R

Art Unit

2624

SEARCHED

| Class | Subclass | Date | Examiner | | |
|-------|----------|-----------|----------|--|--|
| 382 | 319 | 9/28/2008 | SRK | | |
| 358 | 488 | 9/28/2008 | SRK | | |

SEARCH NOTES

| Search Notes | Date | Examiner | | |
|---|-----------|----------|--|--|
| NPL search IEEE explore and INSPEC for pre-scanning methods | 9/28/2008 | SRK | | |

INTERFERENCE SEARCH

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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